



Flash Memory Summit

“The bitterness of poor quality remains long after the sweetness of low price is forgotten.”

– Benjamin Franklin –



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The key to Designing Reliable Storage Systems

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EMBD-101-A-1: Embedded Applications, Part 1 – Drive Design

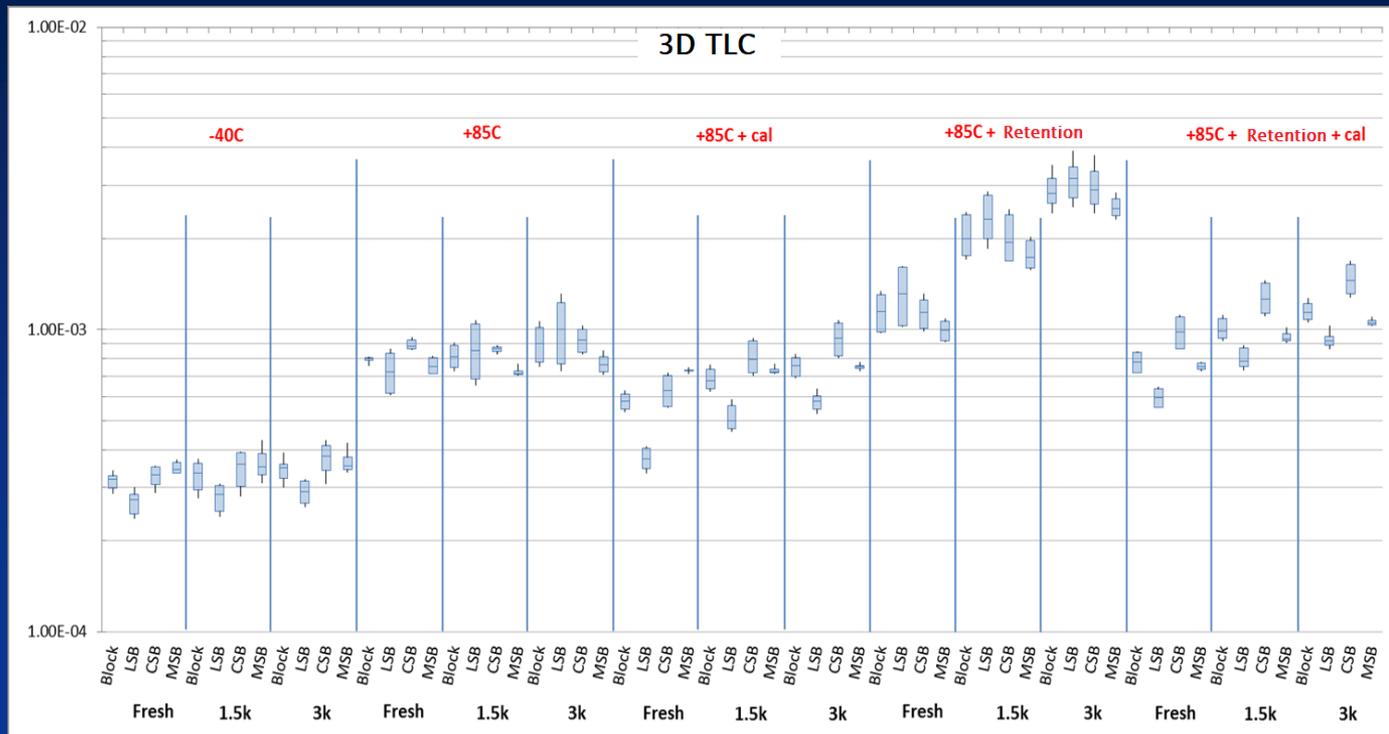


System Level Reliability

- Some quality needs to be by-design
- Our design and reliability target:
Highest correction performance with guaranteed error floor
 - UBER at no less than 1×10^{-16} worst case



Lifetime RBER

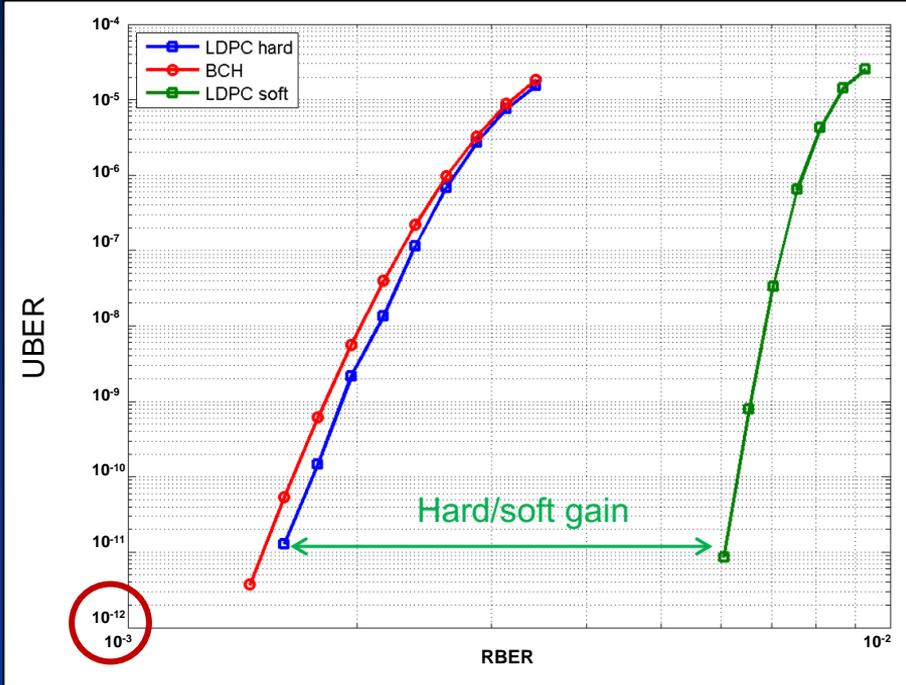


Cross-temp program at -40°C read at different temperatures

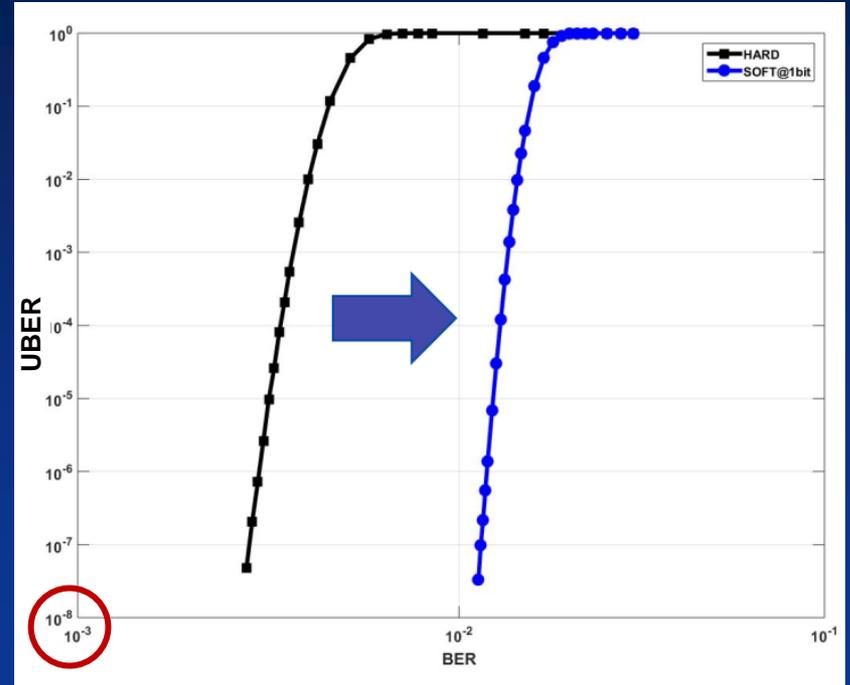
After calibration, RBER between 2×10^{-4} and 2×10^{-3} (EOL & worst case)



Typical ECC performance plots



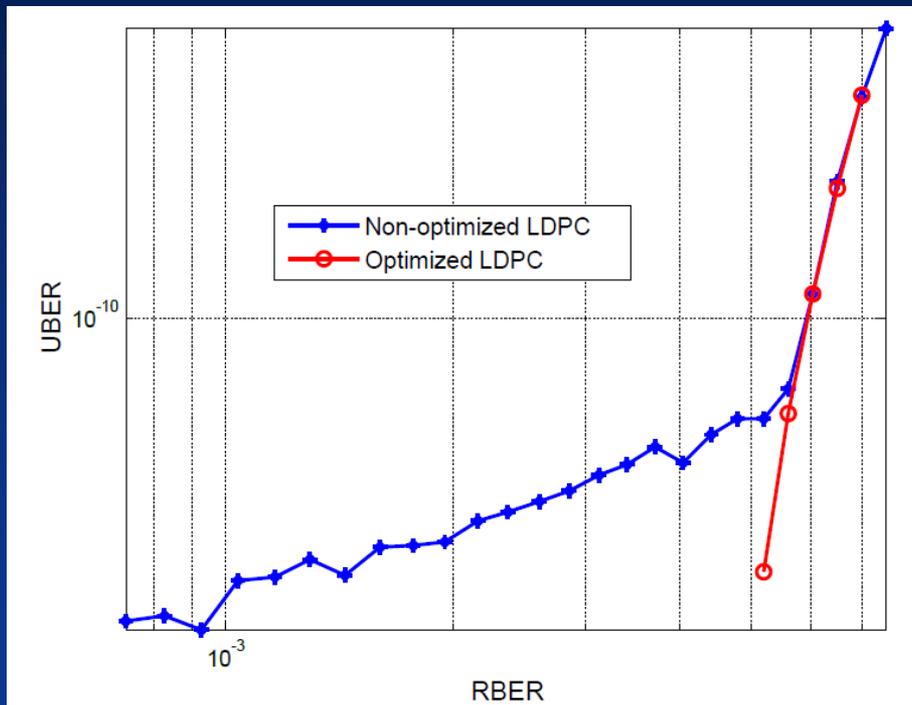
"LDPC Code Concepts and Performance on High-Density Flash Memory", Erich F. Haratsch, Flash Memory Summit 2014



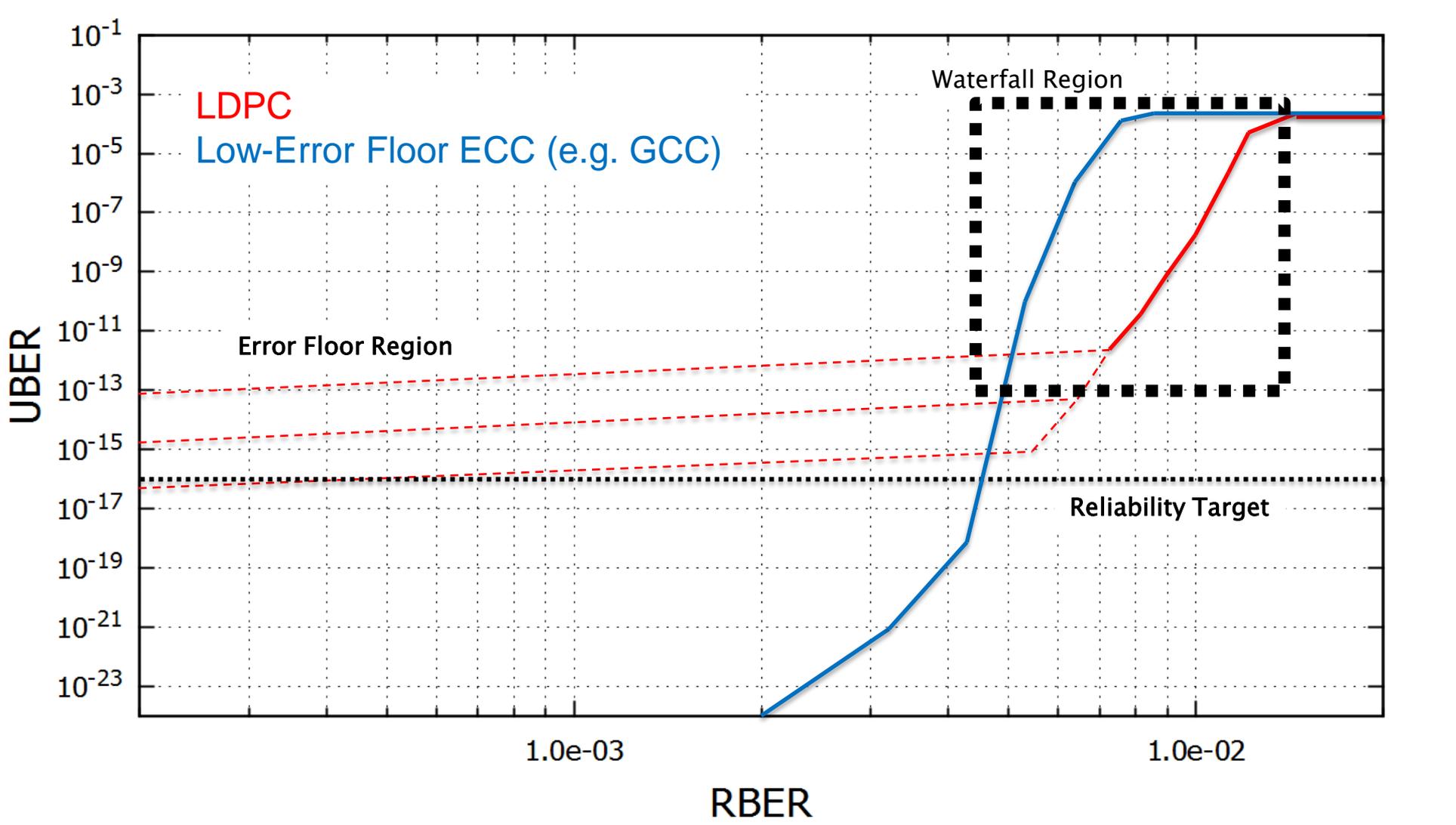
"Fully Integrated LLR Calculation Flow", L. Zuolo, A. Marelli, and R. Micheloni, Flash Memory Summit 2018

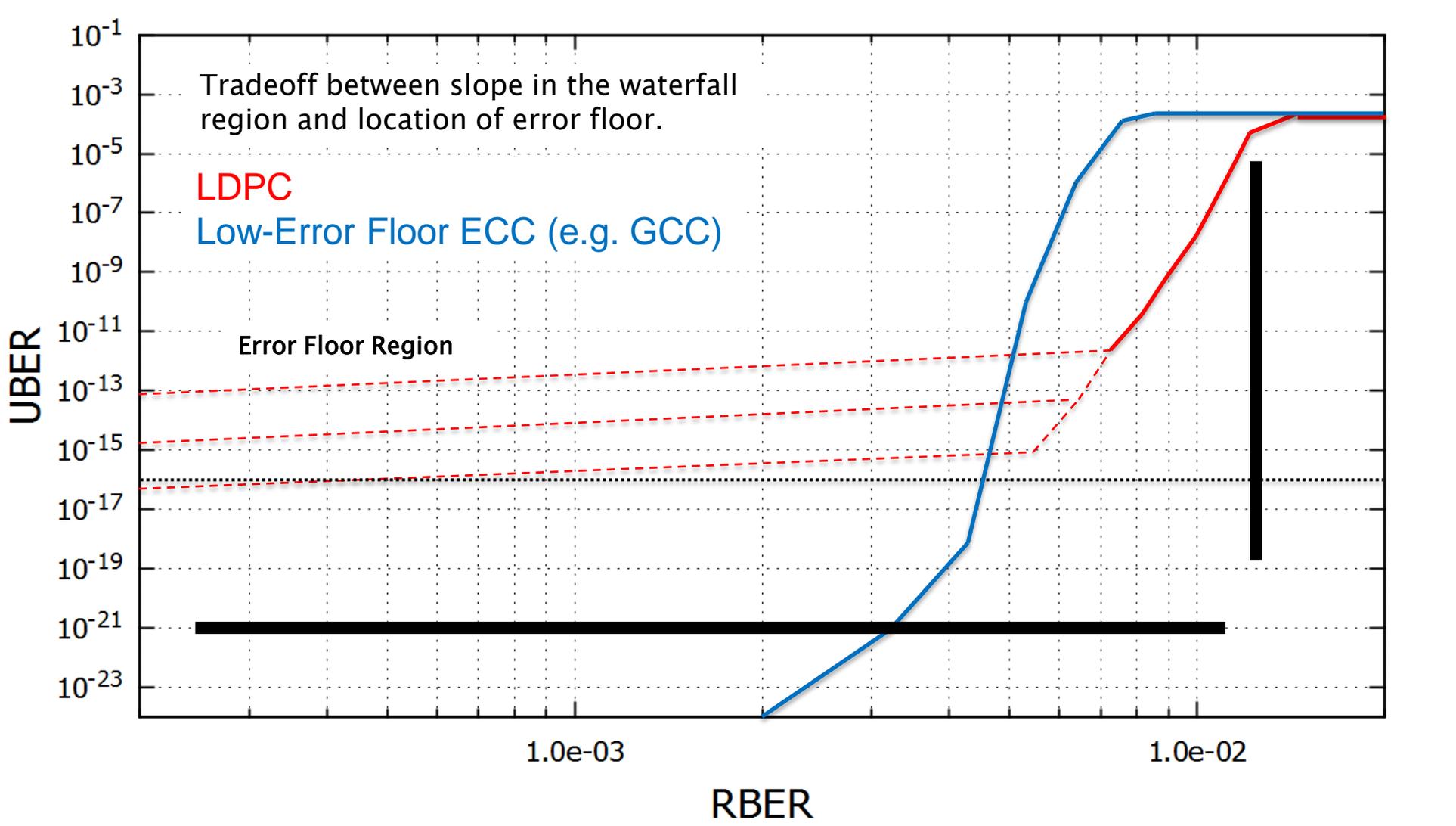


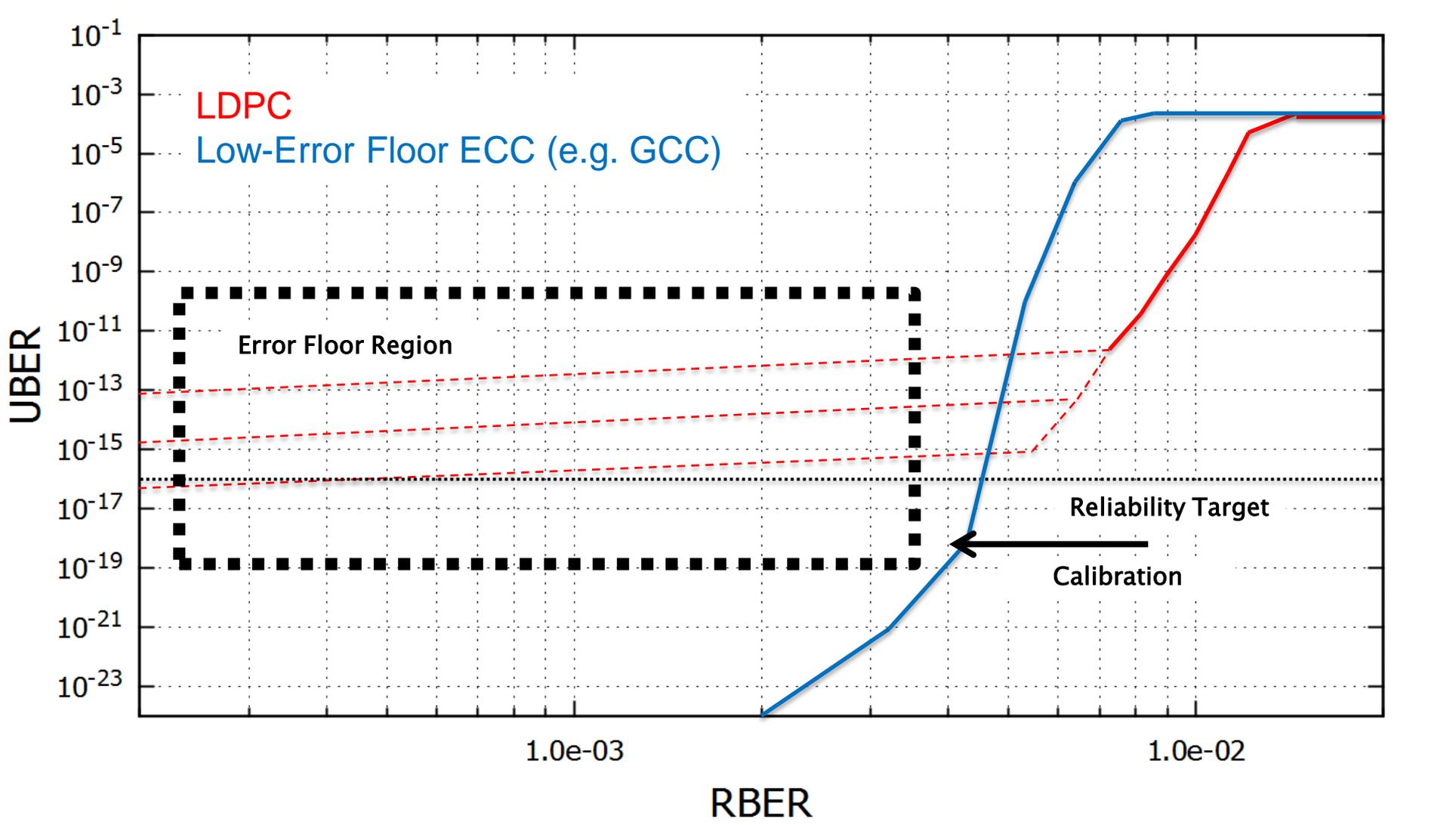
Where exactly is the error floor of the ECC you are using?

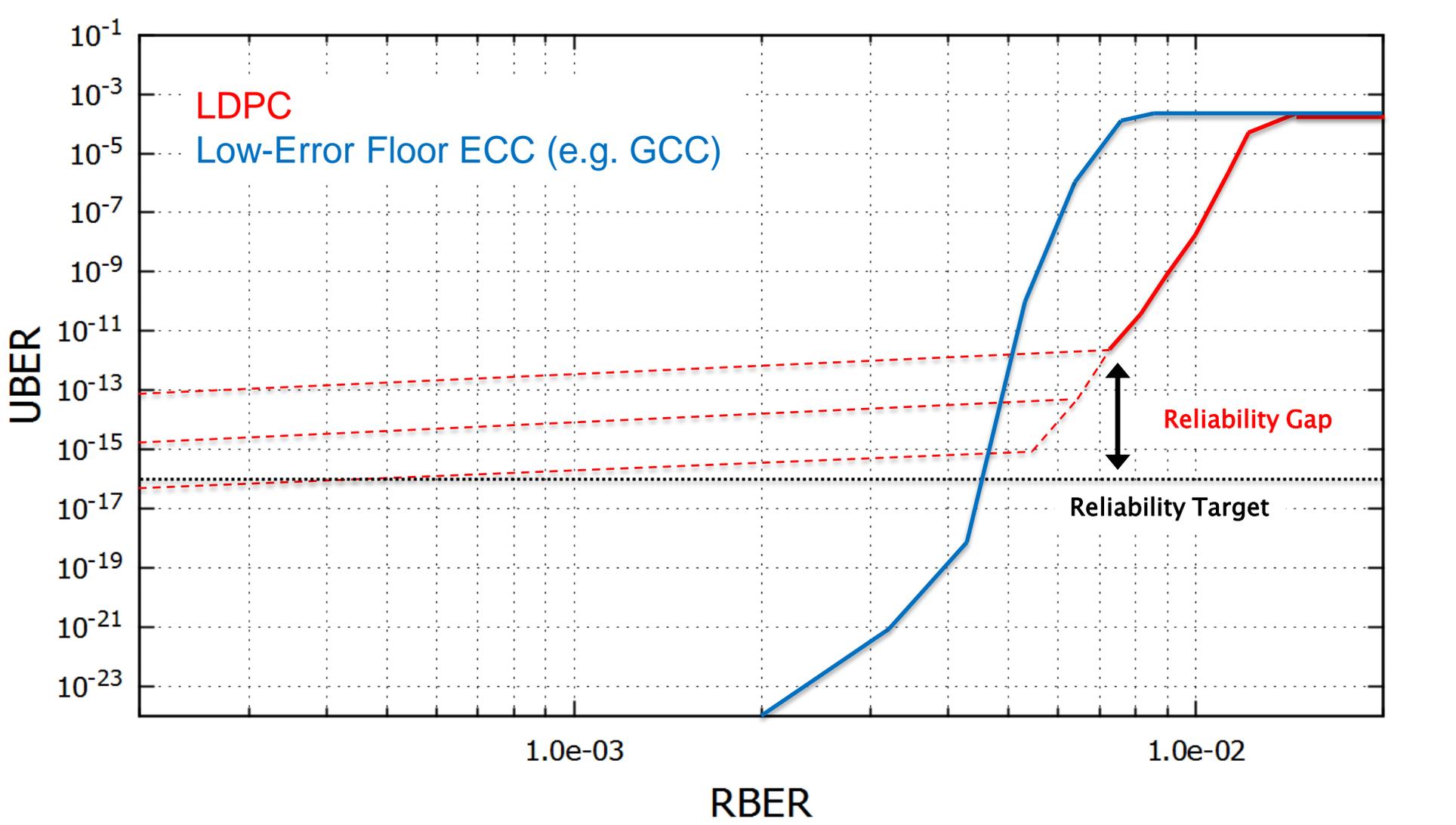


"LDPC Code Concepts and Performance on High-Density Flash Memory", Erich F. Haratsch, Flash Memory Summit 2014









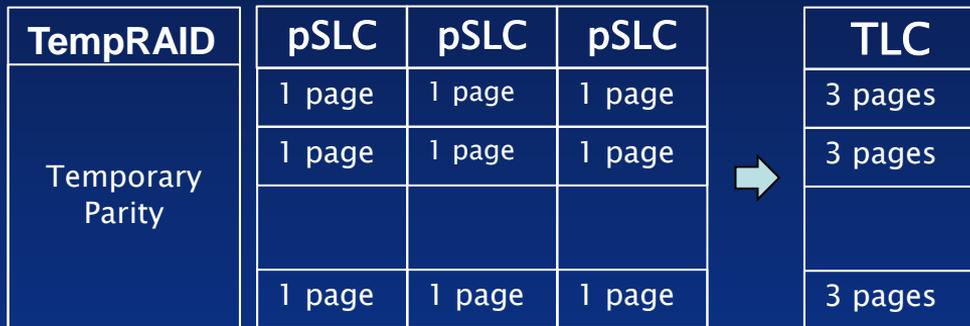


RAID vs. TempRAID

RAID (permanent)

| Block A | Block B | Block C | Block D |
|-----------|-----------|-----------|---------|
| User data | User data | User data | Parity |

TempRAID



Keep pSLC blocks with RAID as backup until TLC block is successfully written

- WAF increase
- Performance impact
- RAID is not always the solution



RAID vs. TempRAID

| Protection Mechanism | Capacity Impact | Recovery Time | Protection Strength |
|--|-----------------|---------------|---|
| RAID (3:1) | High | Medium | High |
| RAID (127:1) | Medium | Large | Medium |
| Read-Verify (temporary SLC RAID) | None | Small | High (if low error-floor ECC is used) |



Summary

- Pushing ECC performance to higher RBER may introduce a higher error floor
- RAID as countermeasure to higher UBER is costly (WAF, capacity, performance)
- Low-Error-Floor ECC (e.g. GCC)
 - Allows cheaper and reliable countermeasure (Read-Verify)
 - Allows different/less-overhead RAID structures



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Final Thoughts...

Your key take away for the summit

- Watch for the error floor
- Is UBER plotted down to 10^{-16} and beyond?
- Don't trust dotted lines – those may be based on assumptions



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*“Small things make perfection, but
perfection is no small thing”*

– Henry Royce –



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The secret to Designing Reliable Storage Systems

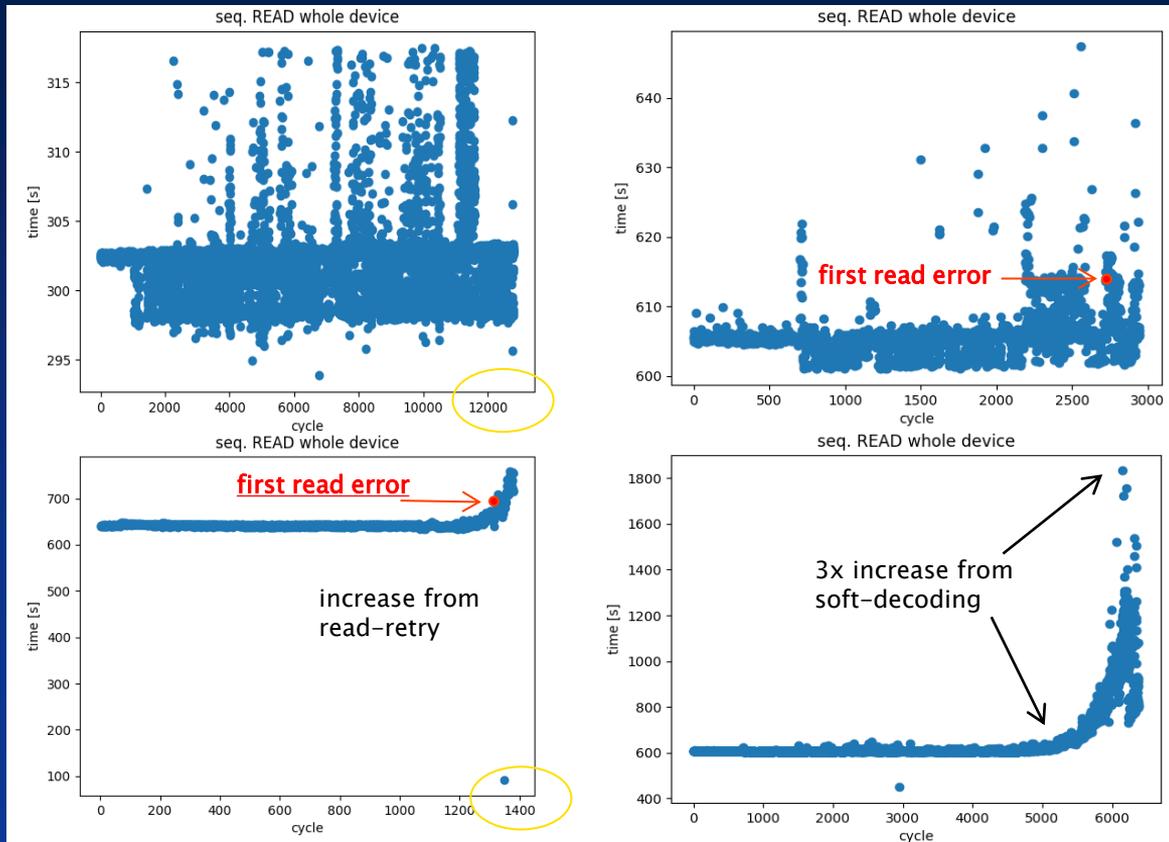
Additional Information



System Level Reliability Tests

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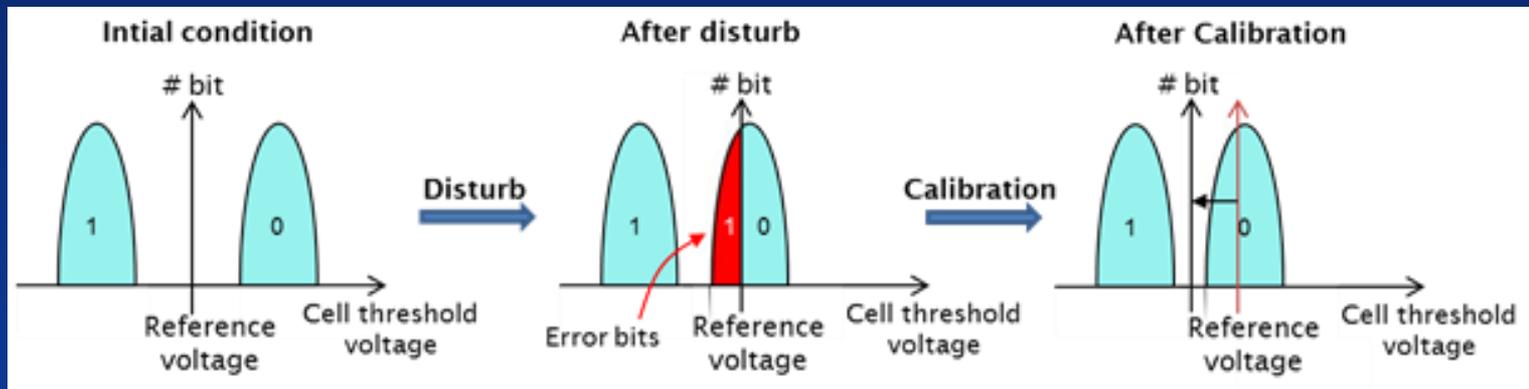
- Subsequent full drive writes (cycles) / drive reads (drive reads plotted in [s])
- Read errors are tracked, first one is highlighted
- Test stops at first failed write command
- 10x difference in lifetime of different SSDs!**





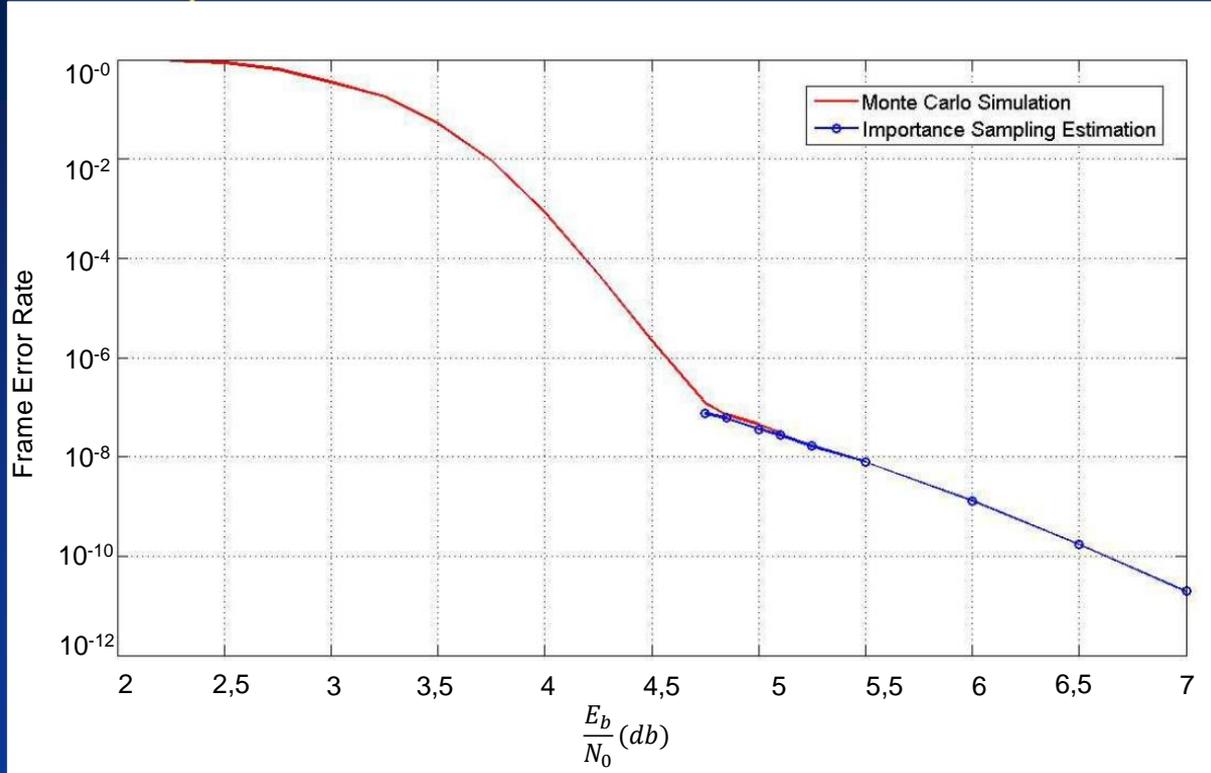
Calibration

Calibration can be carried out by firmware in configurable intervals during operation





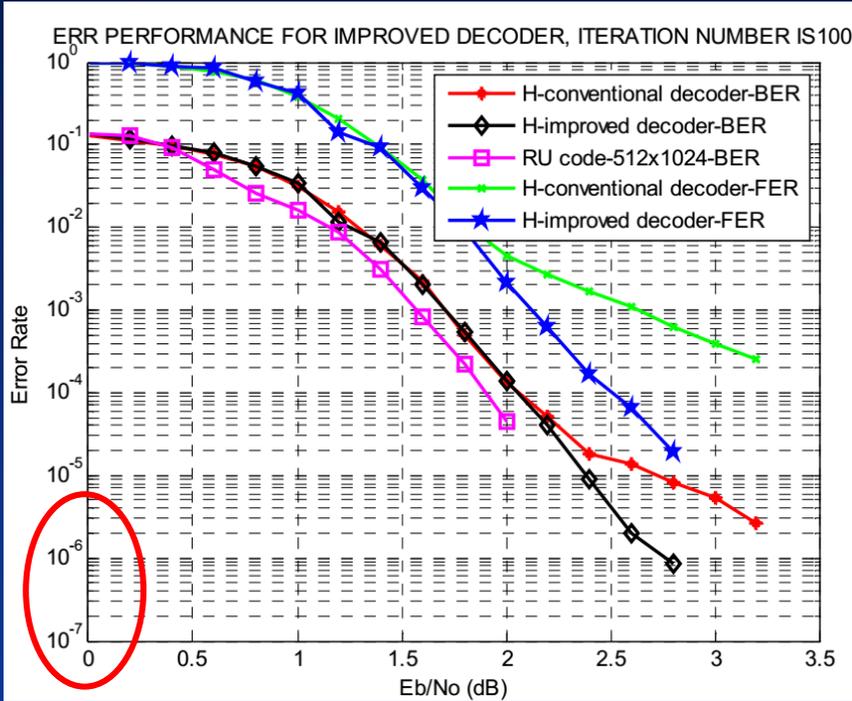
Error Correction



- LDPC codes are not simulated down to JEDEC specified rates ($= 10^{-16}$ for enterprise), but only down to $\sim 10^{-10}$
- For the further trend methods like „importance sampling“ are used where a small subset of the codewords is used for estimation
- This educated guess is an orientation but nothing that can be relied on!**



Error Correction



"Analysis of Error-Prone Patterns for LDPC Codes under Belief Propagation Decoding", Huanlin Li, Yanyan Cao, Jeffrey C. Dill, The 2010 Military Communications Conference

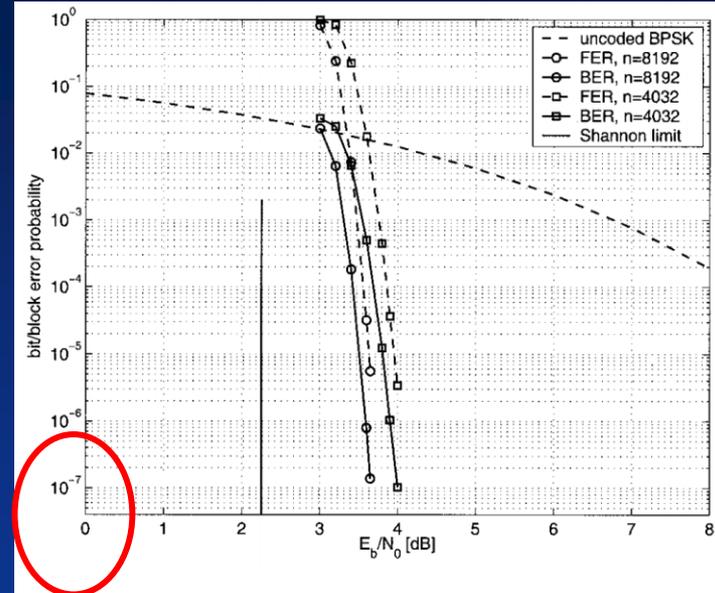


Fig. 2. Error performances of the (8192,6754) RS-based Gallager (6,32)-regular LDPC code with construction field $GF(2^8)$, and the (4032,3307) RS-based Gallager (60,63)-regular quasi-cyclic LDPC code with construction field $GF(2^6)$.

"A Class of Low-Density Parity-Check Codes Constructed Based on Reed-Solomon Codes With Two Information Symbols", Ivana Djurdjevic, Jun Xu, Khaled Abdel-Ghaffar, Member, IEEE, and Shu Lin, Fellow, IEEE, IEEE COMMUNICATIONS LETTERS, VOL. 7, NO. 7, JULY 2003



Error Correction

- LDPC
 - High performance
 - Error-floor unknown – estimation only (e.g. importance sampling)
 - Full simulation not feasible
 - Many different “quality” grades depending on implementation and alignment to specific Flash technology and channel model
- Generalized Concatenated Code (GCC)
 - High correction performance
 - Error-floor: analytical determination possible
 - Low-Error Floor
 - Guaranteed correction capability



UBER

- Two definitions
 - Scientific: Uncorrectable Bit Error Rate – a statistic measure of the probability of one erroneous bit after processing in the the ECC unit (module level).
 - JEDEC: $UBER = \frac{\text{number of data errors (sectors)}}{\text{number of bits read}}$ during the TBW rating limit of the drive (sector errors of the whole system).
 - Large difference between the two depending on the ECC frame size and system sector size

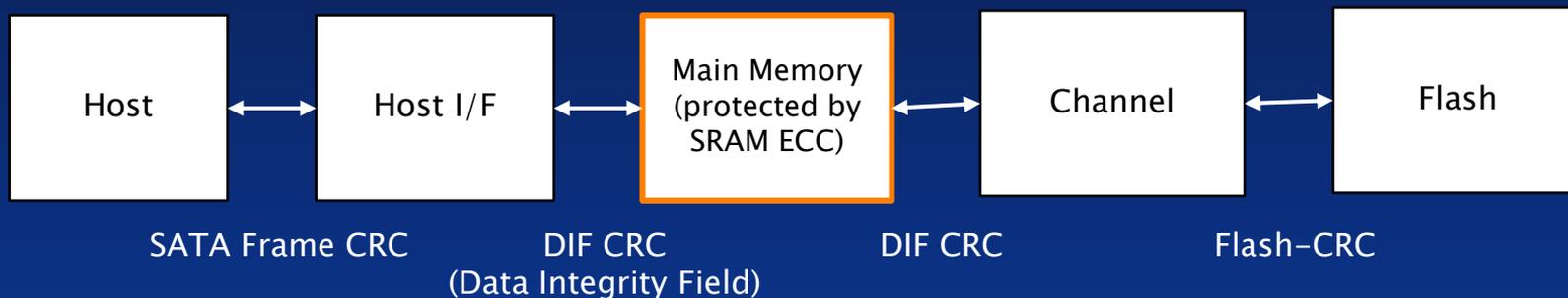


Reliability Enhancement Techniques

| Technique | Impact on Average Read Performance | Impact on Trail Performance (Read) | WAF | Management Overhead |
|-----------------------------------|------------------------------------|------------------------------------|------------|---------------------|
| ECC (hard-decision) | Negligible | None | Negligible | None |
| ECC (soft-decision) | None | High | Negligible | Negligible |
| Read Retry | None | High | None | Voltage levels |
| Flash Calibration | Low | High | None | None |
| RAID (3:1) | High (depending on error floor) | Medium | High | Medium |
| RAID (127:1) | Low (depending on error floor) | High | Medium | Low |
| Temporary RAID (e.g. Read-Verify) | None | None | Medium | Medium |
| Dynamic Data-Refresh | None | None | Low | Low |



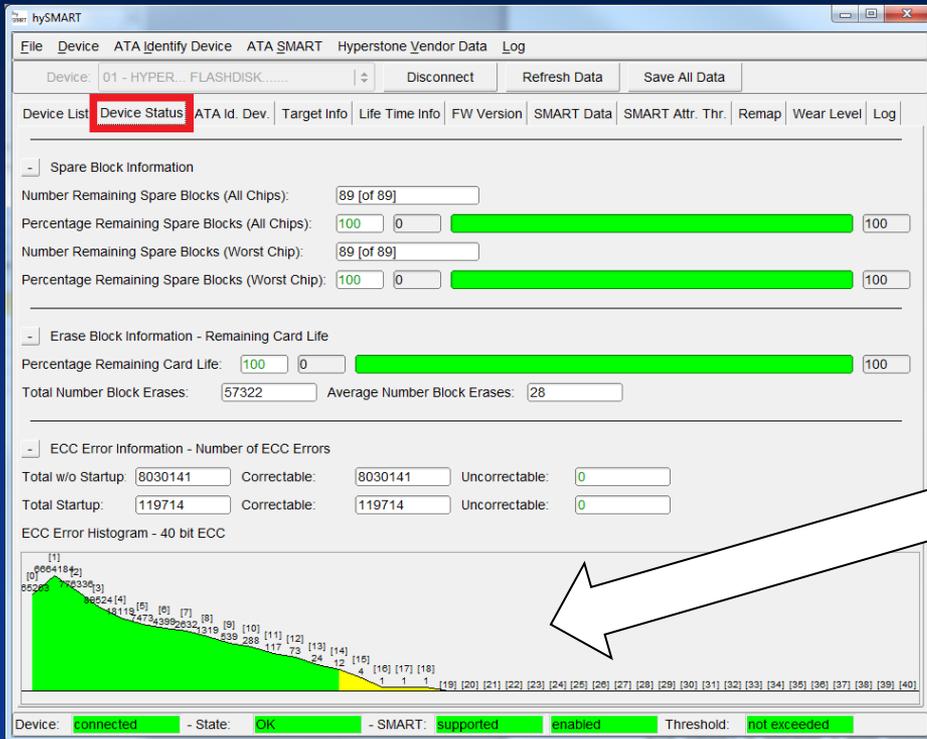
E2E Data-Path Protection



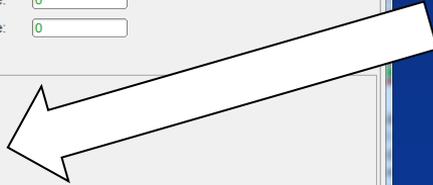
- Protection against radiation (single event effects)
- Detection & correction of errors in the main memory
- Comprehensive protection of the complete datapath



RBER – Lifetime Monitoring



With the Hyperstone **hySMART** tool you can monitor the corrected bit errors during lifetime to be confident your system works within operating conditions and to predict lifetime for your specific use-case and mission profile.





hyReliability FlashXE[®]

FlashXE[®]



eXtended Endurance – Hardware and Firmware Features

Qualification

Near Miss ECC

Dynamic Data-Refresh

Calibration

Read Retry

Low-error floor
ECC

Read Disturb
Management

RAID

Read Verify